SLOVENSKI STANDARD
SIST EN IEC 60749-23:2026

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Nadomešča:
SIST EN 60749-23:2004
SIST EN 60749-23:2004/A1:2011

Polprevodniški elementi - Metode za mehansko in klimatsko preskušanje - 23. del: Obratovalna življenjska doba pri visoki temperaturi (IEC 60749-23:2025)

Semiconductor devices - Mechanical and climatic test methods - Part 23: High temperature operating life (IEC 60749-23:2025)

Halbleiterbauelemente - Mechanische und klimatische Prüfverfahren - Teil 23: Lebensdauer bei hoher Temperatur (IEC 60749-23:2025)

Dispositifs à semiconducteurs - Méthodes d'essais mécaniques et climatiques - Partie 23: Durée de vie en fonctionnement à haute température (IEC 60749-23:2025)

Ta slovenski standard je istoveten z: **EN IEC 60749-23:2026**

ICS:

19.020	Preskuševalni pogoji in postopki na splošno	Test conditions and procedures in general
31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general

SIST EN IEC 60749-23:2026 **en**

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EUROPÄISCHE NORM

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Semiconductor devices - Mechanical and climatic test methods - Part 23: High temperature operating life (IEC 60749-23:2025)

Dispositifs à semiconducteurs - Méthodes d'essais mécaniques et climatiques - Partie 23 : Durée de vie en fonctionnement à haute température
(IEC 60749-23:2025)

Halbleiterbauelemente - Mechanische und klimatische Prüfverfahren - Teil 23: Lebensdauer bei hoher Temperatur
(IEC 60749-23:2025)

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European Committee for Electrotechnical Standardization
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Europäisches Komitee für Elektrotechnische Normung

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European foreword

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Endorsement notice

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